

ReRAM Compute ASIC Fabrication

Team: Sddec24-13

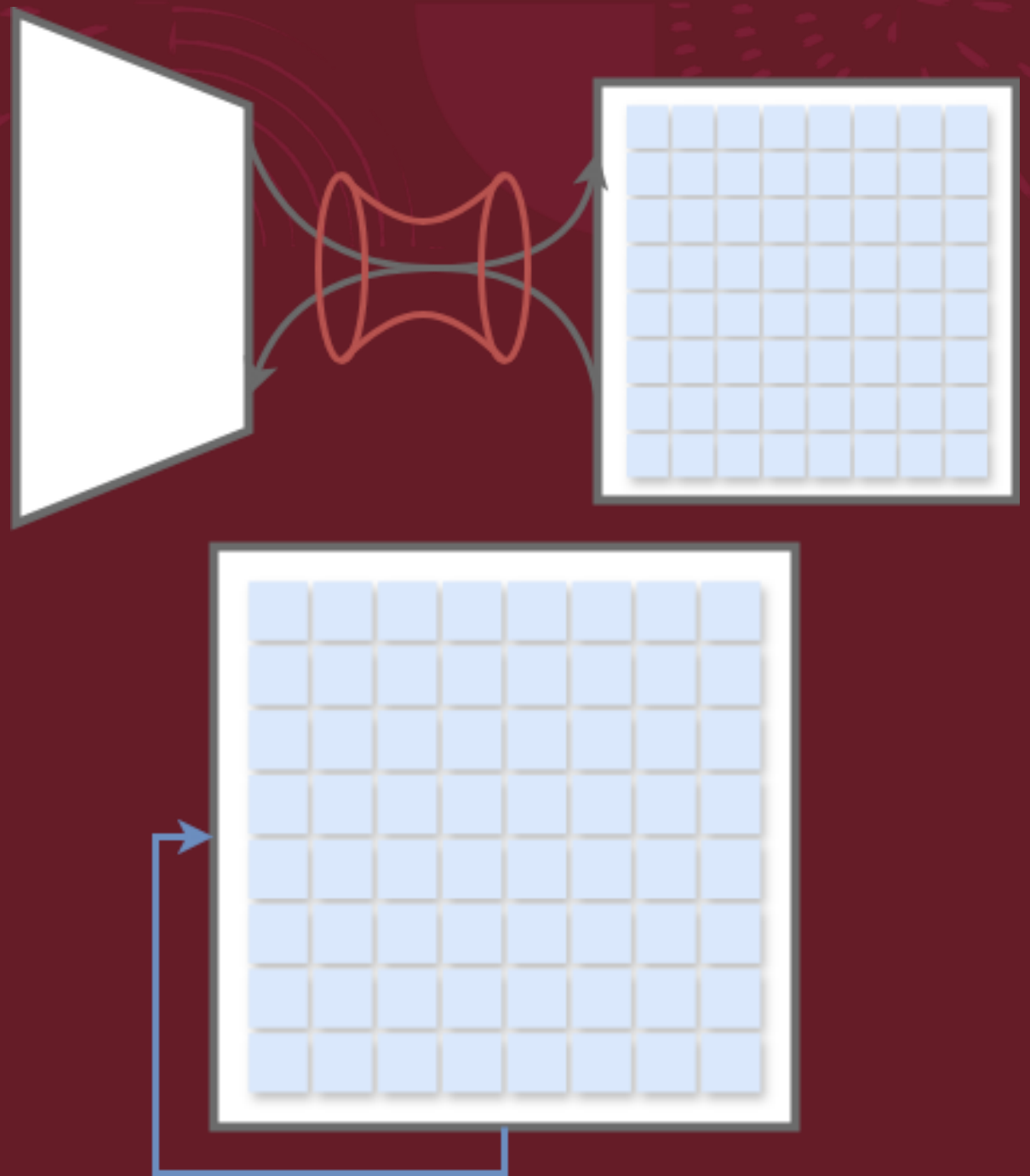
Members: Konnor Kivimagi, Jason Xie, Gage Moorman, Nathan Cook

Client: Dr. Henry Duwe

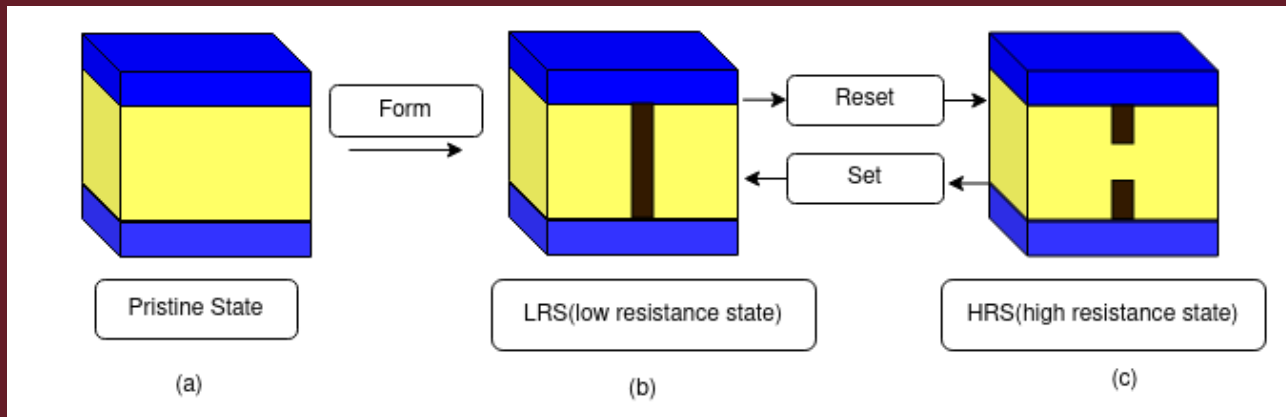
Advisor: Dr. Cheng Wang

Broad context

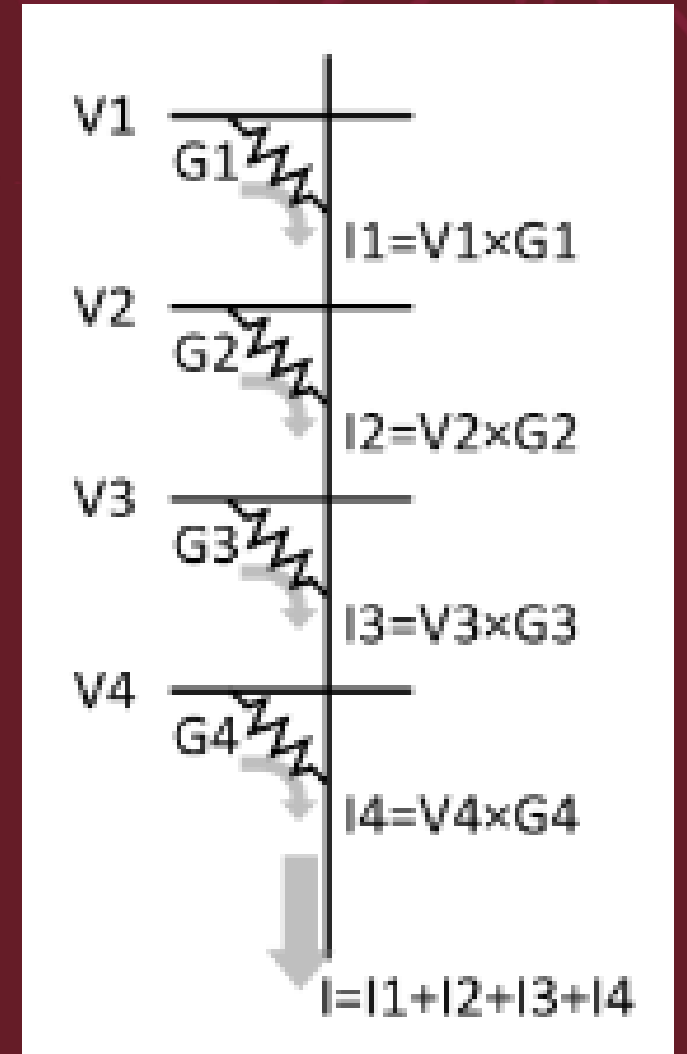
- Machine learning...
 - Bottlenecked by data transfer from memory to CPU
- In memory computation using matrix multiplication can solve the bottleneck



ReRAM



How ReRAM works



Source 2

ReRAM MAC

ReRAM pros and cons

Pros	Cons
High memory density	Variation due to random noise
Non-volatile memory	Different manufacturing process
Low power consumption	Not an established technology
Ability to scale to smaller processes	

Problem Statement

- Problem statement
 - Create a research vehicle for silicon proving computational resistive random access memory for research and educational purposes
- Goals
 - Create a design to be fabricated through the Efabless ChipIgnite program
 - Create documentation for future students to be able to test our design

Efabless Fabrication

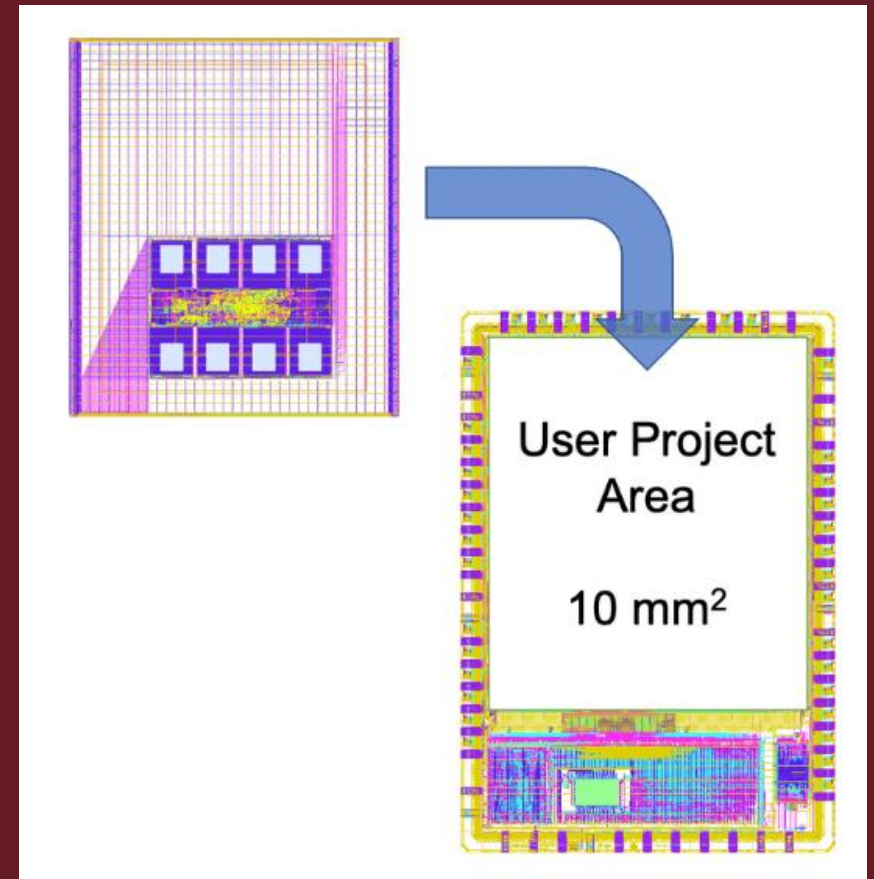


Efabless runs a shuttle program every few months

- Low cost development
- Projects are required to be open-source
- Uses Skywater 130nm process

Design Process

- Create a design
- Integrate it into the caravel harness
- Submit for fabrication



Source 1

Users



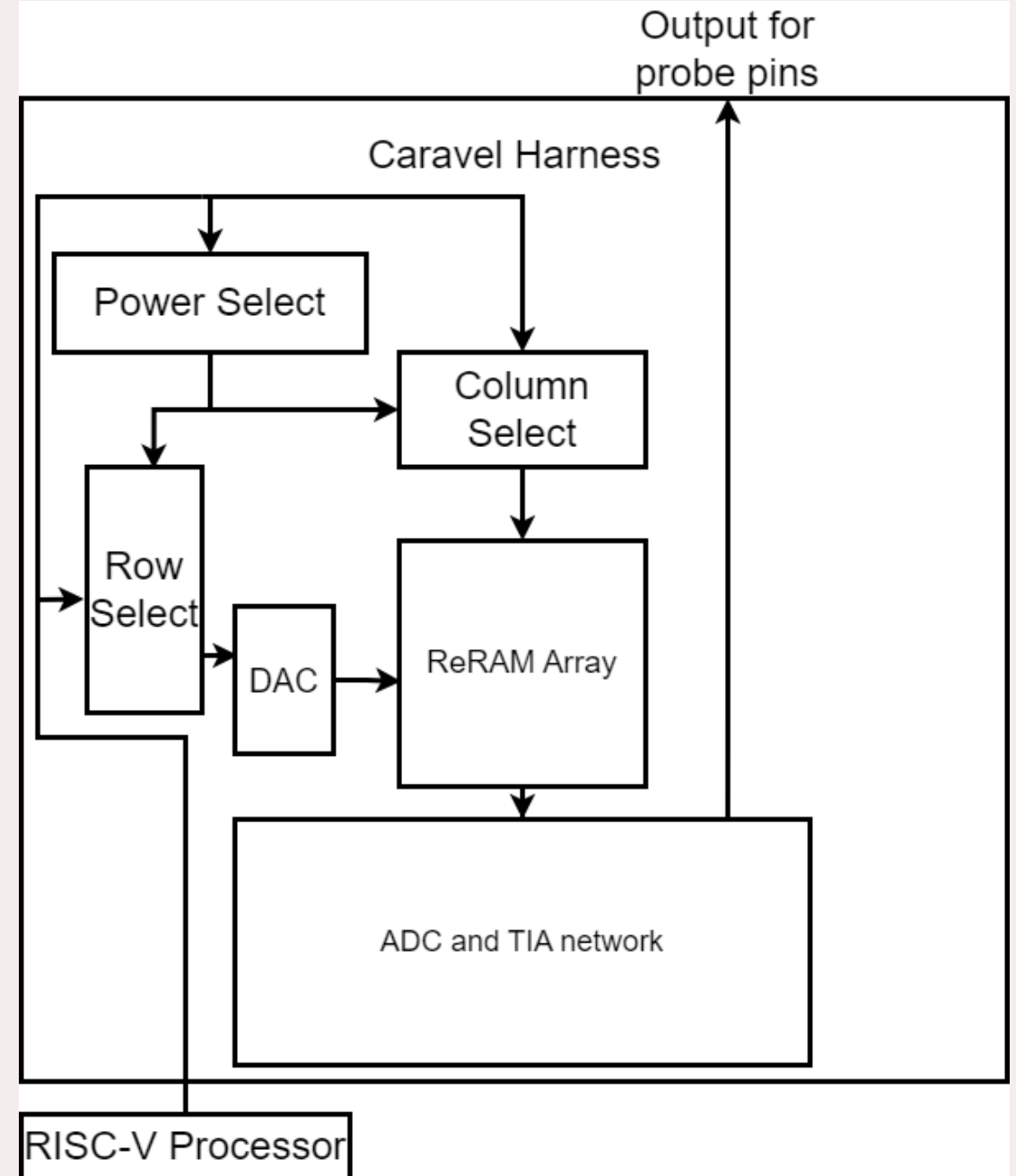
- Graduate Students
 - Documentation on Efabless process and tool flow
- Undergrad Students
 - Easy to follow lab documentation
 - Gain the ability to bring up a chip in parallel with their regular coursework
- Professor Duwe and Professor Wang
 - Practical example of a crossbar for research and testing
 - Provide valuable resources for the co-curricular chip program

Requirements

- Functional Requirements
 - Design an 8x8 ReRAM crossbar that can perform matrix vector multiplication
 - Create an ADC with a sufficient resolution
 - 1MHz clock speed
 - Minimize area
- Non-functional Requirements
 - Project Documentation
 - Bring-up plan for testing the fabricated chip

Top level design

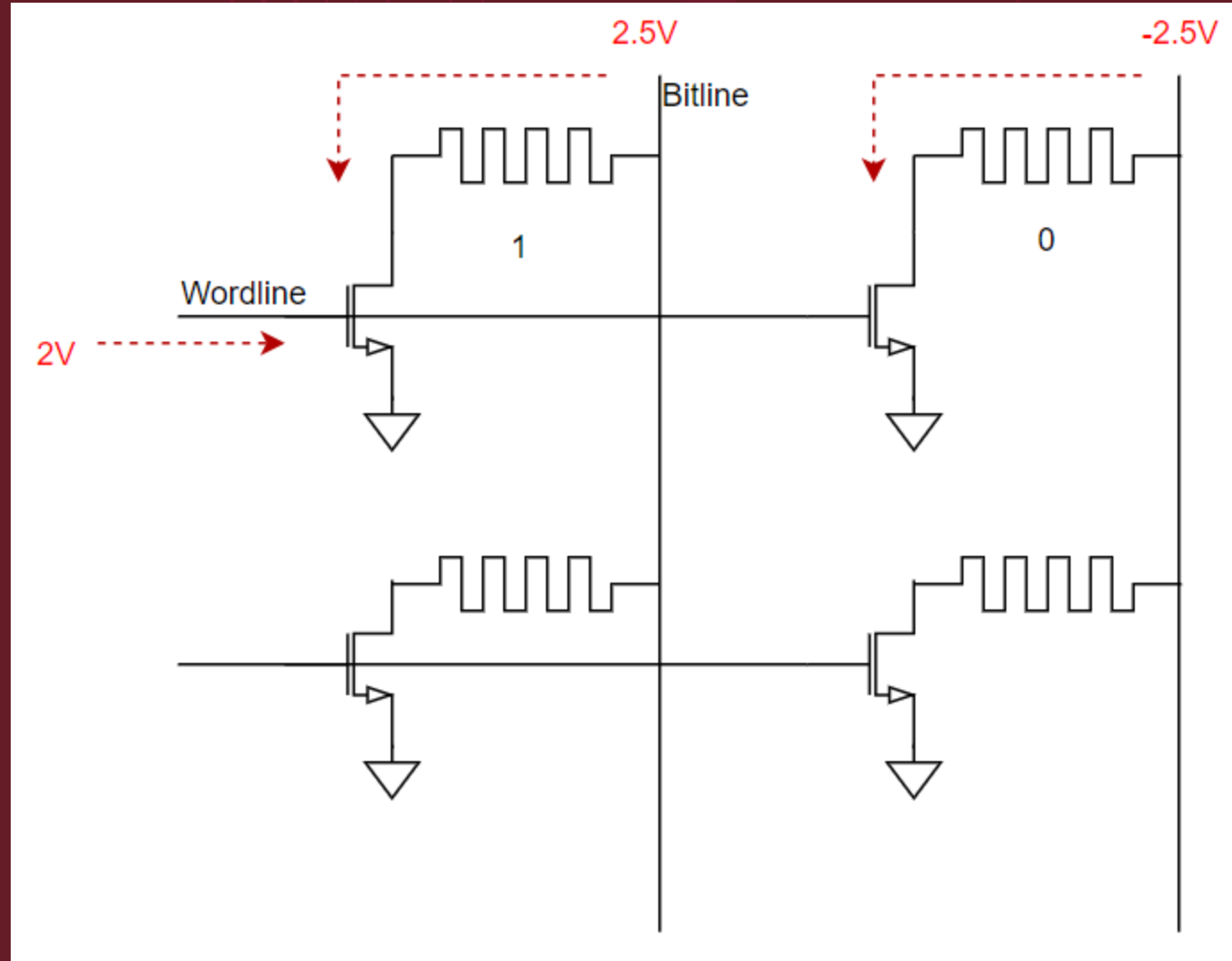
- Control circuits – Logic analyzer, row, power, and column select, decides what operation is performed
- DAC – used during standalone operation
- Power select – selects the voltage values being used
- ADC and TIA network – Convert ReRAM analog output to a logic analyzer compatible digital output



ReRAM operations

Write

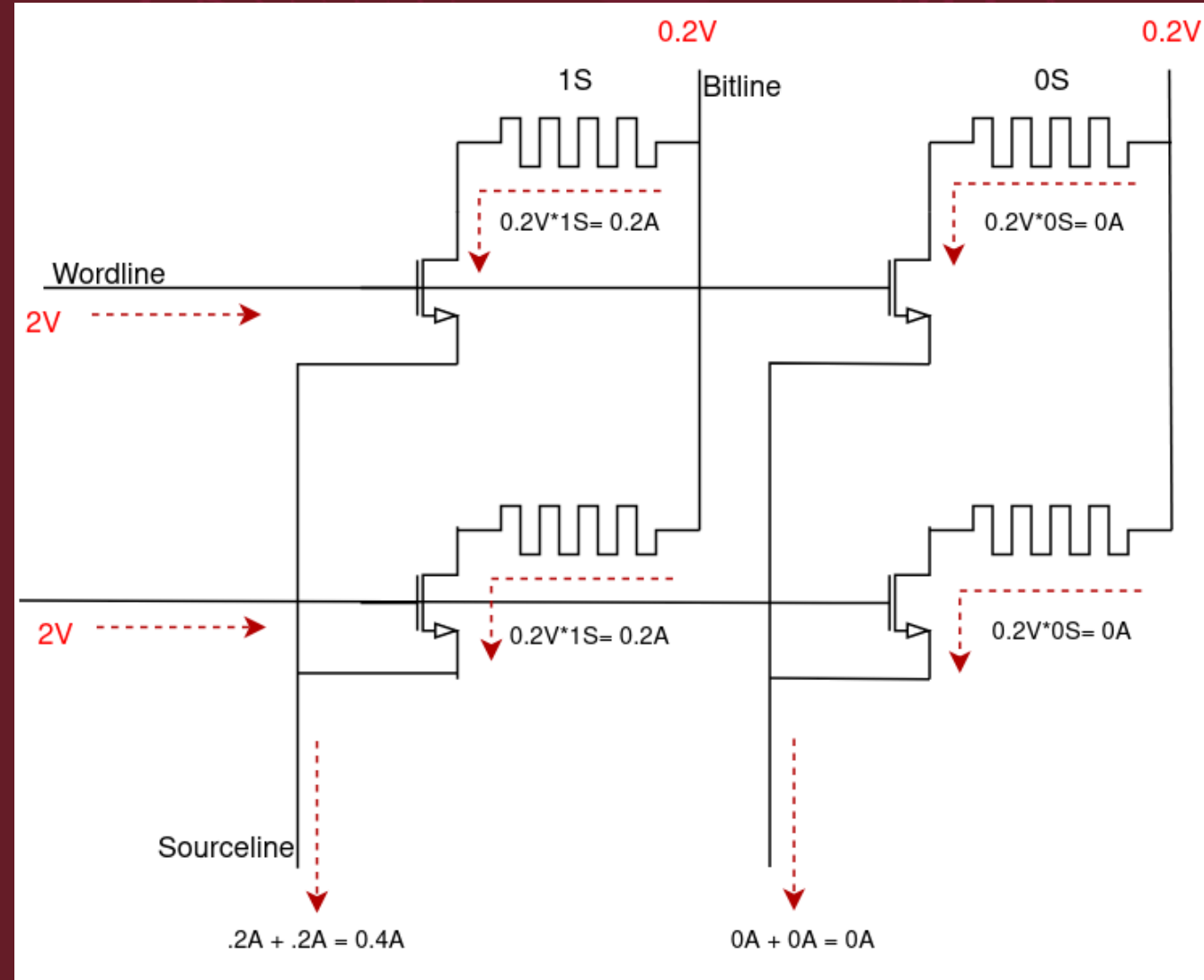
- Bitline selects column
 - Also chooses the written value
- Wordline selects row



ReRAM Operations

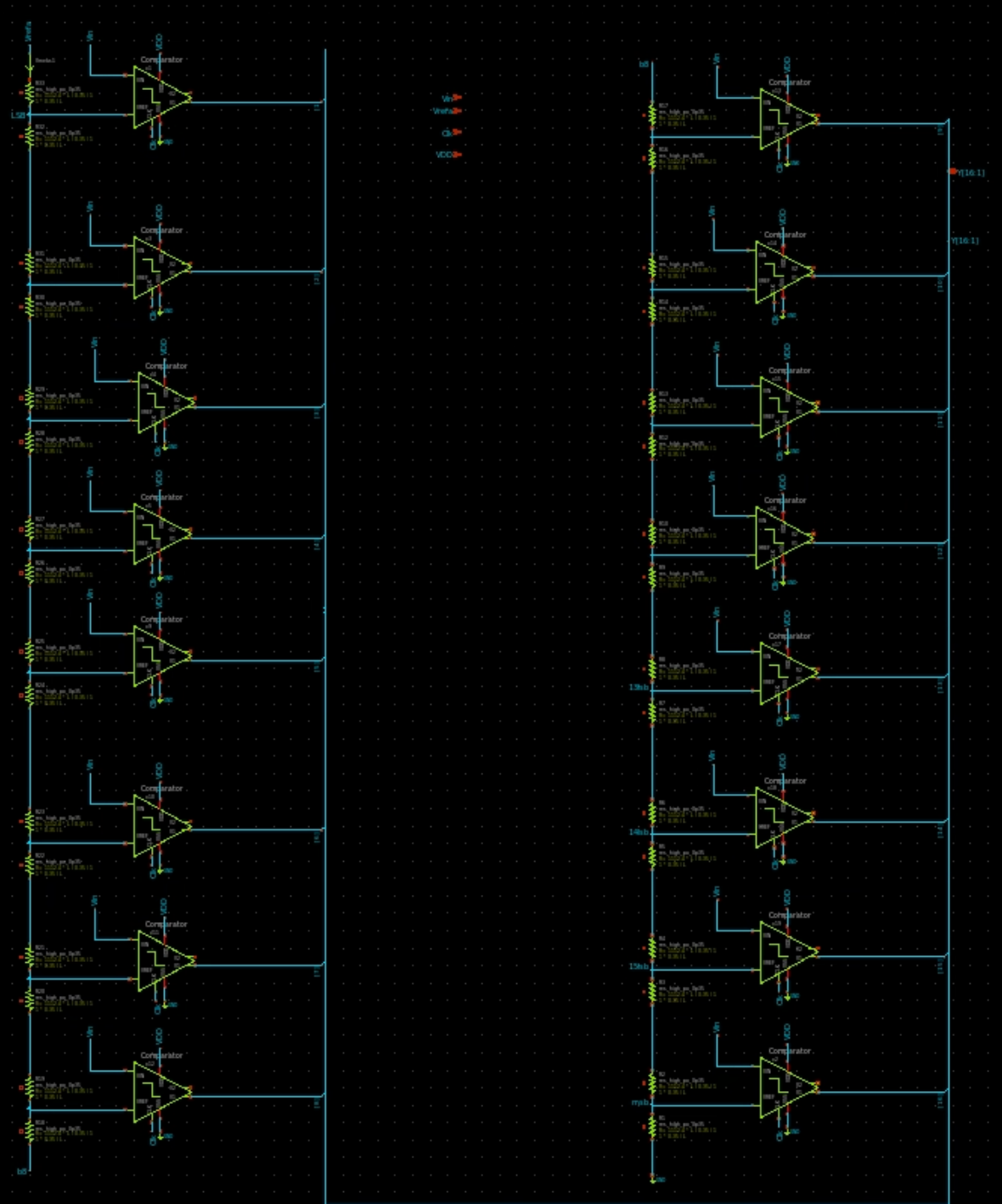
MAC/read

- Currents add
- Resistor multiplies
 - $I = VG$
 - $G = 1/R$



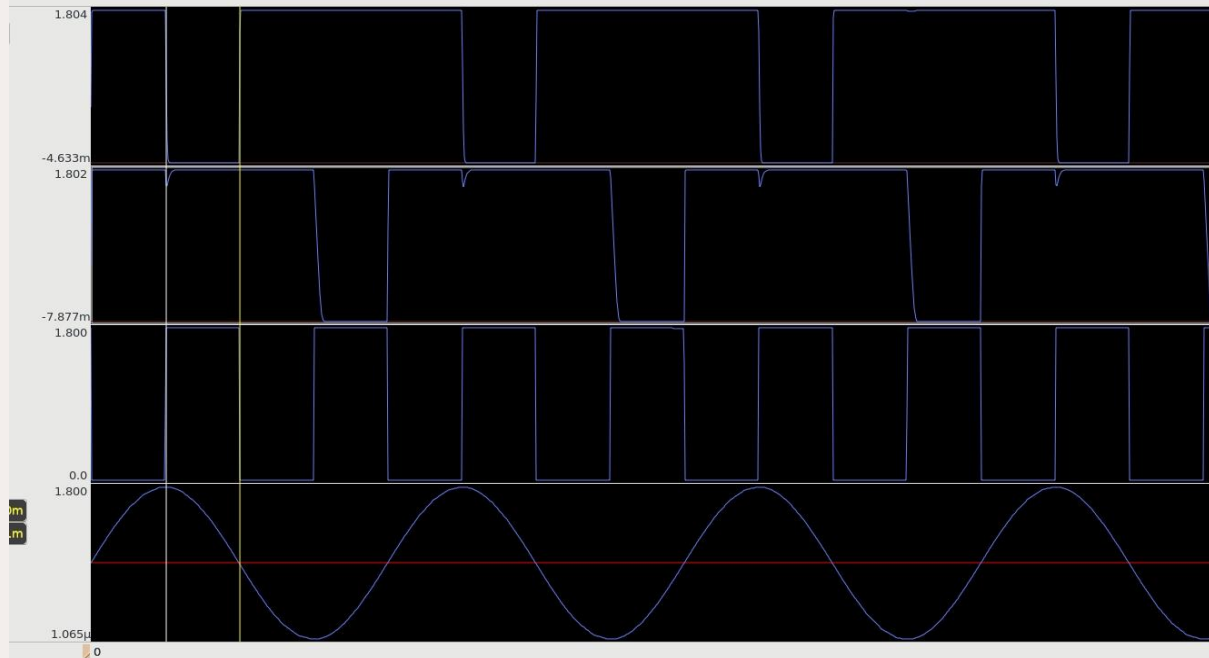
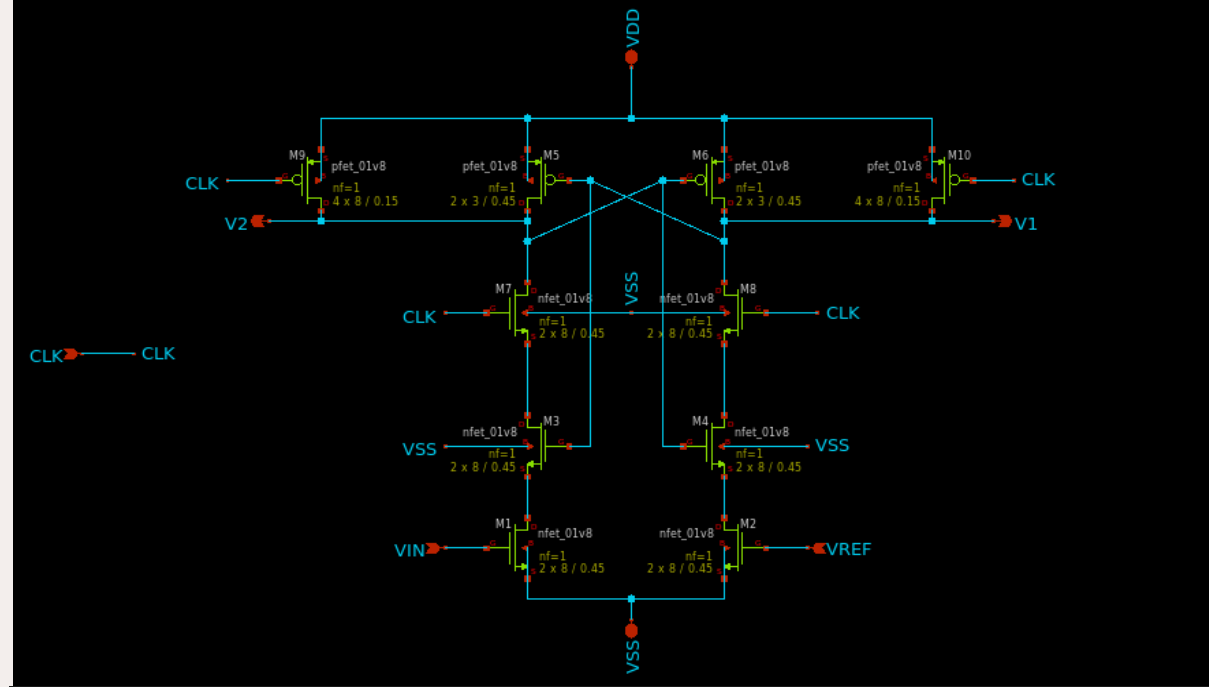
ADC

- Flash ADC
 - Simple
 - Fast
- 4-bit resolution
- SNR 25.84 dB
- Other testing still in progress



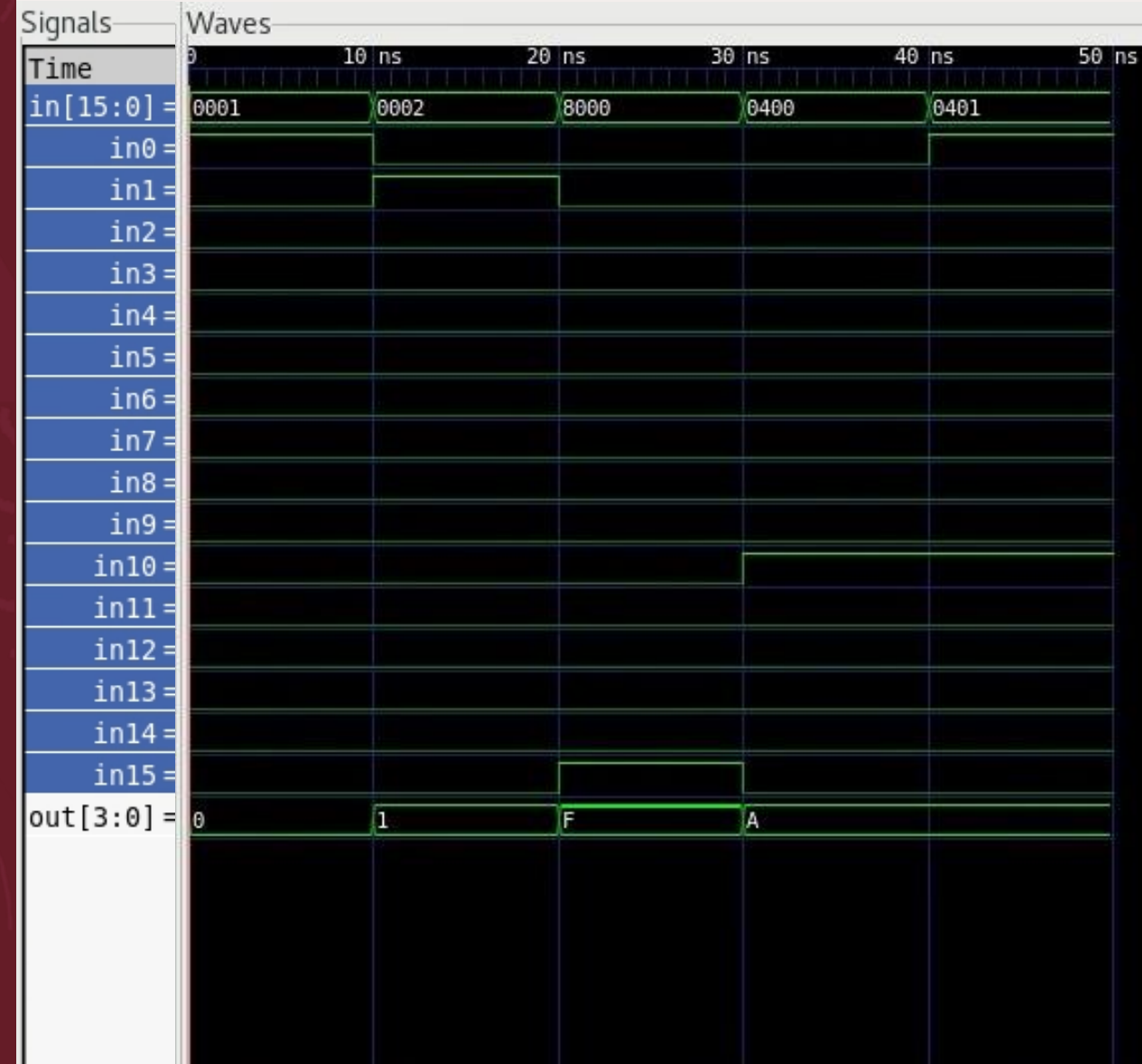
Comparator

- StrongARM Comparator
 - Zero static power consumption
 - Rail to rail outputs
 - Reduction in input referred offset voltage



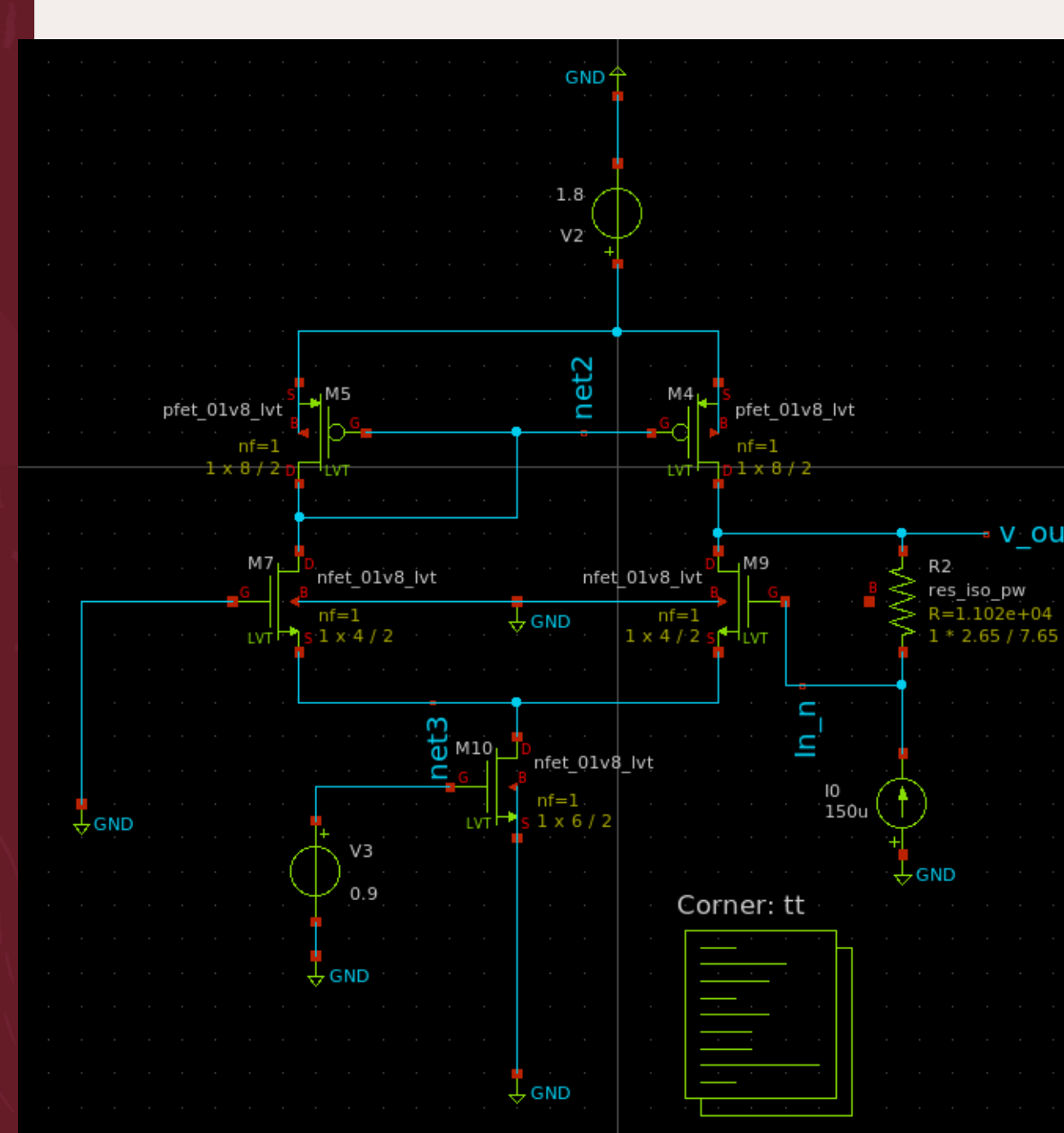
Priority Encoder

- Used for thermometer to binary encoding
- One-hot encoding
- Fully digital component
 - To be implemented with OpenLane "blackboxing"



TIA

- 5T op-amp with feedback resistor
 - Very simple to implement
 - Insufficient input swing
- 7T op-amp with feedback resistor
 - Requires a capacitor
 - Reasonable input swing

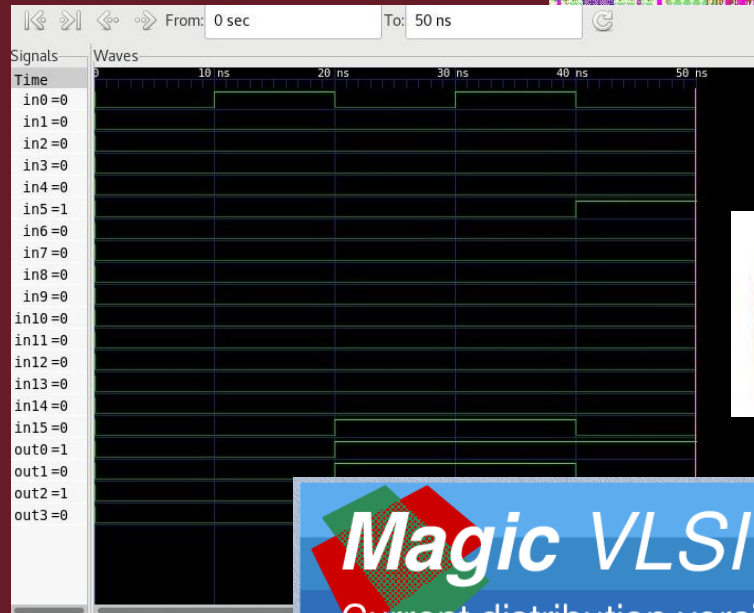


Risk Mitigation

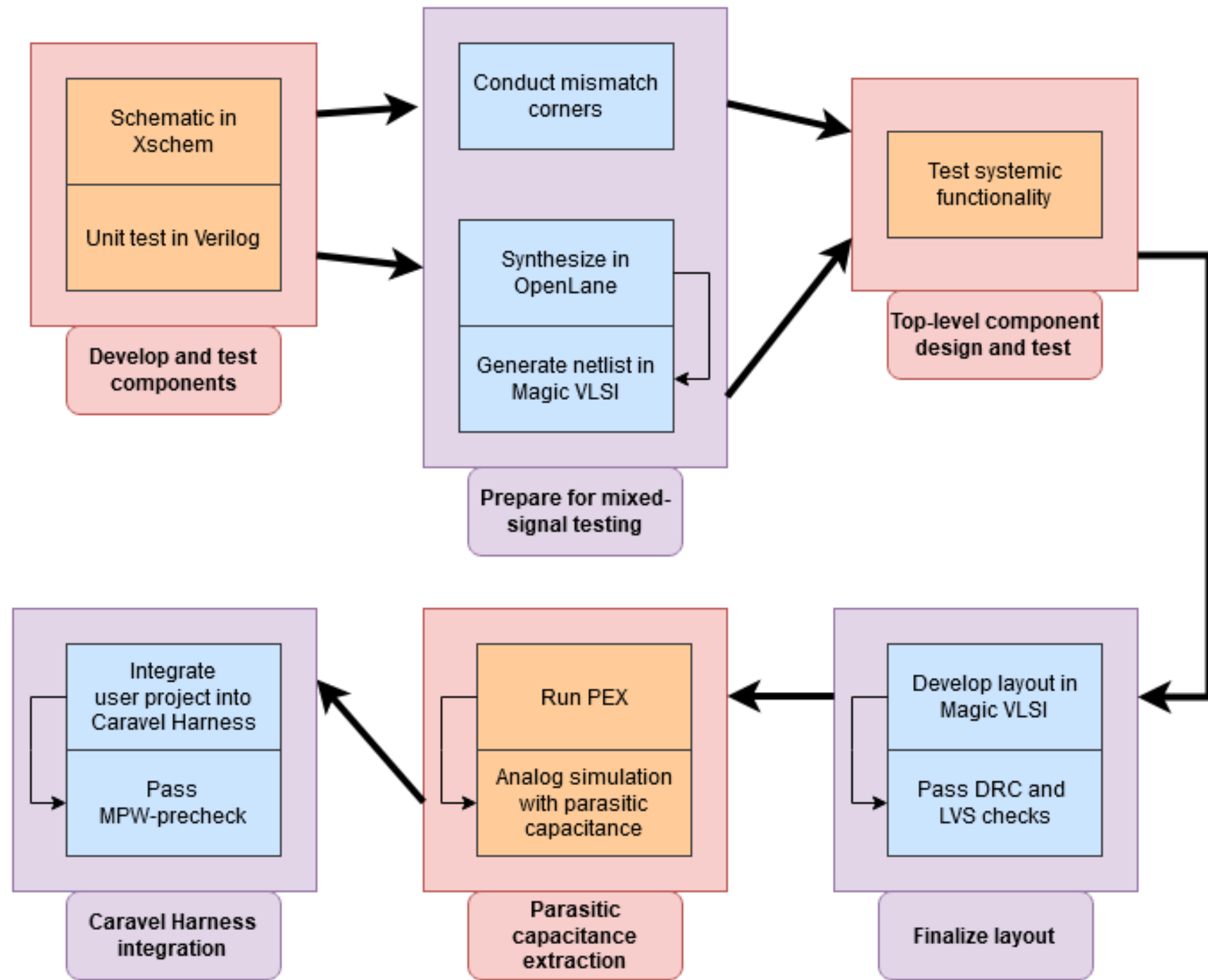
- Peripheral Circuits Delay
 - Risk: Peripheral circuits may not be completed on time.
 - Mitigation: Thorough planning, use of Cadence, simplification of designs.
- Memristor and CMOS Modeling Issues
 - Risk: Inaccurate memristor model and inconsistent CMOS transistor simulation.
 - Mitigation: Explore open-source SPICE models, document current issues, propose future solutions.
- Fabrication Errors
 - Risk: Design constraints not met due to fabrication errors.
 - Mitigation: Detailed bring-up plan with testing methods, acknowledge limitations in preventing fabrication errors.

Design Tools

- Xschem - Schematic capture
- Netgen - Used for LVS
- Ngspice - Spice simulator
- Magic - Layout creation
- Klayout - GDSII viewer
- GTKwave - Verilog waveforms



Testing Plan



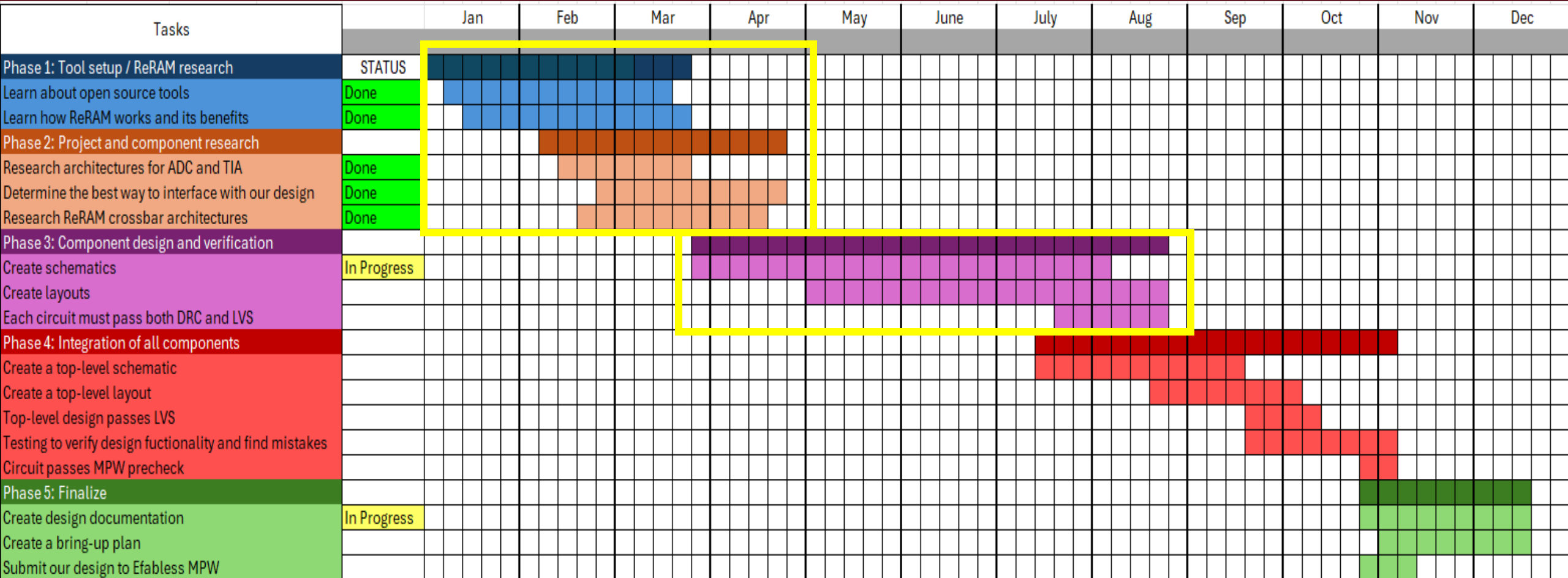
Project Status

Component	Planning	Design	Testing	Layout
DAC	Green	Green	Green	Green
ADC	Green	Yellow	White	White
TIA	Green	Green	Yellow	White
ReRAM Crossbar	Green	Green	Yellow	White
Control circuits	Yellow	White	White	White

Immediate next steps:

- Finalize ADC components
- Conduct ADC and TIA testing
- Complete full ReRAM array
- Contribute to co-curricular ChipFab documentation
- Verify control instruction sets

Timeline



Work Breakdown

Gage Moorman

- ADC design

Konnor Kivimagi

- Analog tool setup
- ReRAM design

Jason Xie

- Digital tool setup
- TIA design

Nathan Cook

- Control circuits design

Conclusion

Accomplishments:

- Analog design toolflow
- Digital design toolflow

Component progress:

- DAC realization
- ADC architecture research
- ReRAM crossbar operation and simulation
- TIA parameter extraction

Plans for next semester:

- Mixed signal integration
- Finish sizing ADC and TIA
- Complete control circuitry
- Develop bringup test plan
- Update documentation

A 3D rendering of a large yellow question mark standing on a field of smaller, dark grey question marks. The background is a dense field of these question marks, creating a textured, almost abstract landscape. The lighting is dramatic, with strong highlights and deep shadows, giving the scene a sense of depth and focus on the central yellow question mark.

Questions?

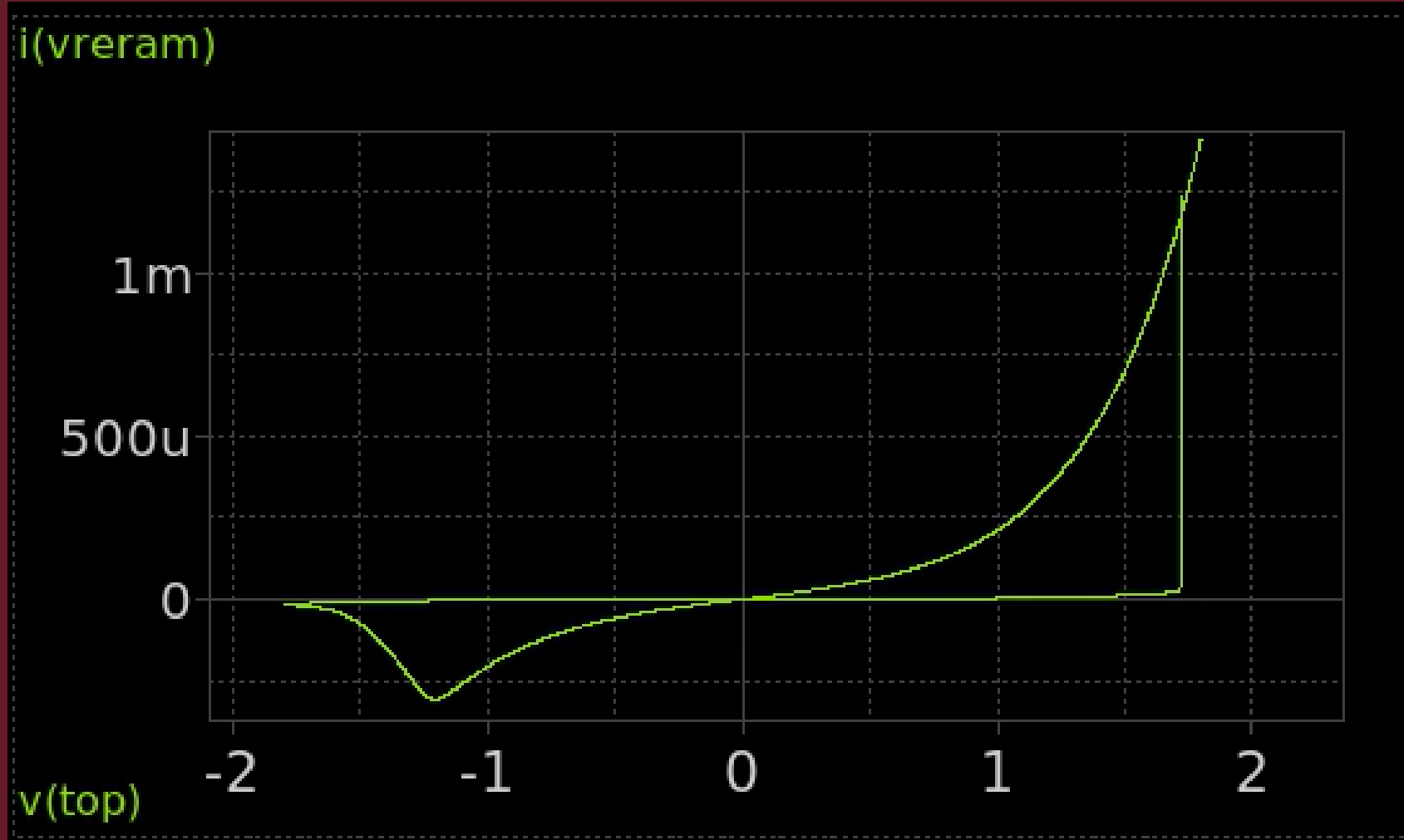


Supplementary Slides

Definitions

- DRC : Design Rule Check
- LVS: Layout vs Schematic
- MPW: Multi-Project Wafer
- Efabless: Chip design company
- ReRAM: Resistive Random Access Memory
- ASIC: Application Specific Integrated Circuit
- ADC: Analogue to Digital Converter
- DAC: Digital to Analogue Converter
- TIA: Transimpedance Amplifier

ReRAM IV Curve



Sources

- 1) <https://efabless.com/chipignite>
- 2) https://web.eecs.umich.edu/~zhengya/papers/chou_micro19.pdf
- 3) <http://opencircuitdesign.com/magic/>
- 4) <https://semiwiki.com/semiconductor-manufacturers/tsmc/287672-in-memory-computing-for-low-power-neural-network-inference/>
- 5) Tony Chan Carusone, D. Johns, and K. W. Martin, *Analog integrated circuit design*. Hoboken, Nj Wiley, 2012.
- 6) B. Razavi, "The StrongARM Latch [A Circuit for All Seasons]," in *IEEE Solid-State Circuits Magazine*, vol. 7, no. 2, pp. 12-17, Spring 2015, doi: 10.1109/MSSC.2015.2418155.